Digital Testing Scan Path Design Ohio University

How to design for optimum maintenance capabilities and minimize the repair time Design for Maintainability offers engineers a wide range of tools and techniques for incorporating maintainability into the design process for complex systems. With contributions from noted experts on the topic, the book explains how to design for optimum maintenance capabilities while simultaneously minimizing the time to repair equipment. The book contains a wealth of examples and the most up-to-date maintainability design practices that have proven to result in better system readiness, shorter downtimes, and substantial cost savings over the entire system life cycle, thereby, decreasing the Total Cost of Ownership. Design for Maintainability offers a wealth of design practices not covered in typical engineering books, thus allowing readers to think outside the box when developing maintainability design requirements. The book's principles and practices can help engineers to dramatically improve their ability to compete in global markets and gain widespread customer satisfaction. This important book: Offers a complete overview of maintainability engineering as a system engineering discipline Includes contributions from authors who are recognized leaders in the field Contains real-life design examples, both good and bad, from various industries Presents realistic illustrations of good maintainability design principles Provides discussion of the interrelationships between maintainability with other related disciplines Explores trending topics in technologies Written for design and logistics engineers and managers, Design for Maintainability is a comprehensive resource containing the most reliable and innovative techniques for improving maintainability when designing a system or product.

An Introduction to Logic Circuit Testing provides a detailed coverage of techniques for test generation and testable design of digital electronic circuits/systems. The material covered in the book should be sufficient for a course, or part of a course, in digital circuit testing for senior-level undergraduate and first-year graduate students in Electrical Engineering and Computer Science. The book will also be a valuable resource for engineers working in the industry. This book has four chapters. Chapter 1 deals with various types of faults that may occur in very large scale integration (VLSI)-based digital circuits. Chapter 2 introduces the major concepts of all test generation techniques such as redundancy, fault coverage, sensitization, and backtracking. Chapter 3 introduces the key concepts of testability, followed by some ad hoc design-for-testability rules that can be used to enhance testability of combinational circuits. Chapter 4 deals with test generation and response evaluation techniques used in BIST (built-in self-test) schemes for VLSI chips. Table of Contents: Introduction / Fault Detection in Logic Circuits / Design for Testability / Built-in Self-Test / References

This book is about digital system testing and testable design. The concepts of testing and testability are treated together with digital design practices and methodologies. The book uses Verilog models and testbenches for implementing and explaining fault simulation and test generation algorithms. Extensive use of Verilog and Verilog PLI for test applications is what distinguishes this book from other test and testability books. Verilog eliminates ambiguities in test algorithms and BIST and DFT hardware architectures, and it clearly describes the architecture of the testability hardware and its test sessions. Describing many of the on-chip decompression algorithms in Verilog helps to evaluate these algorithms in terms of hardware overhead and timing, and thus feasibility of using them for System-on-Chip designs. Extensive use of testbenches and testbench development techniques is another unique feature of this book. Using PLI in developing testbenches and virtual testers provides a powerful programming tool, interfaced with hardware described in Verilog. This mixed hardware/software environment facilitates description of complex test programs and test strategies.

New, updated and expanded topics in the fourth edition include: EBCDIC, Grey code, practical applications of flip-flops, linear and shaft encoders, memory elements and FPGAs. The section on fault-finding has been expanded. A new chapter is dedicated to the interface between digital components and analog voltages. *A highly accessible, comprehensive and fully up to date digital systems text *A well known and respected text now revamped for current courses *Part of the Newnes suite of texts for HND/1st year modules

Testing of Digital Systems
A Unified Approach
An Introduction to Logic Circuit Testing
Desk Reference

Modern Techniques

Device testing represents the single largest manufacturing expense in the semiconductor industry, costing over $40 billion a year. The most comprehensive and wide ranging book of its kind, Testing of Digital Systems covers everything you need to know about this vitally important subject. Starting right from the basics, the authors take the reader through automatic test pattern generation, design for testability and built-in self-test of digital circuits before moving on to more advanced topics such as IDDQ testing, functional testing, delay fault testing, memory testing, and fault diagnosis. The book includes detailed treatment of the latest techniques including test generation for various fault models, discussion of testing techniques at different levels of integrated circuit hierarchy and a chapter on system-on-a-chip test synthesis. Written for students and engineers, it is both an excellent senior/graduate level textbook and a valuable reference.

This book is a self-contained introduction to all aspects of microelectronic (IC) testing. It includes the theory necessary for advanced students as well as reference to industrial practice and economics that will interest designers in industry. Chapters cover both digital circuit testing and the growing area of mixed circuits, used particularly in signal processing.

A pragmatic approach to testing electronic systems As we move ahead in the electronic age, rapid changes in technology pose an ever-increasing number of challenges in testing electronic products. Many practicing engineers are involved in this arena, but few have a chance to study the field in a systematic way-learning takes place on the job. By covering the fundamental disciplines in detail, Principles of Testing Electronic Systems provides design engineers with the much-needed knowledge base. Divided into five major parts, this highly useful reference relates design and tests to the development of reliable electronic products; shows the main vehicles for design verification; examines designs that facilitate testing; and investigates how testing is applied to random logic, memories, FPGAs, and microprocessors. Finally, the last part offers coverage of advanced test solutions for today's very deep submicron designs. The authors take a phenomenological approach to the subject matter while providing readers with plenty of opportunities to explore the foundation in detail. Special features include: * An explanation of where a test belongs in the design flow * Detailed discussion of scan-path and ordering of scan-chains * BIST solutions for embedded logic and memory blocks * Test methodologies for FPGAs * A chapter on testing system on a chip * Numerous references

In response to tremendous growth and new technologies in the semiconductor industry, this volume is organized into five, information-rich sections. Digital Design and Fabrication surveys the latest advances in computer architecture and design as well as the technologies used to manufacture and test them. Featuring contributions from leading experts, the book also includes a new section on memory and storage in addition to a new chapter on nonvolatile memory technologies. Developing advanced concepts, this sharply focused book— Describes new technologies that have become driving factors for the electronic industry Includes new information on semiconductor memory circuits, whose development best illustrates the phenomenal progress encountered by the fabrication and technology sector Contains a section dedicated to issues related to system power consumption Describes reliability and testability of computer systems Pinpoints trends and state-of-the-art advances in fabrication and CMOS technologies Describes performance evaluation measures, which are the bottom line from the user's point of view Discusses design techniques used to create modern computer systems, including high-speed computer arithmetic and high-frequency design, timing and clocking, and PLL and DLL design

Digital Logic Testing and Simulation
Digital and Mixed Analogue/digital Techniques
VLSI Testing
Digital Logic Design
Digital Integrated Circuit Design
Low-power HF Microelectronics

The Electronic Device Failure Analysis Society proudly announces the Seventh Edition of the Microelectronics Failure Analysis Desk Reference, published by ASM International. The new edition will help engineers improve their ability to verify, isolate, uncover, and identify the root cause of failures. Prepared by a team of experts, this updated reference offers the latest information on advanced failure analysis tools and techniques, illustrated with numerous real-life examples. This book is geared to practicing engineers and for studies in the major area of power plant engineering. For non-metallurgists, a chapter has been devoted to the basics of material science, metallurgy of steels, heat treatment, and structure-property correlation. A chapter on materials for boiler tubes covers composition and application of different grades of steels and high temperature alloys currently in use as boiler tubes and future materials to be used in supercritical, ultra-supercritical and advanced ultra-supercritical thermal power plants. A comprehensive discussion on different mechanisms of boiler tube failure is the heart of the book. Additional chapters detailing the role of advanced material characterization techniques in failure investigation and the role of water chemistry in tube failures are key contributions to the book.

It is a great honor to provide a few words of introduction for Dr. Georges Gielen's and Prof. Willy Sansen's book "Symbolic analysis for automated design of analog integrated circuits". The symbolic analysis method presented in this book represents a significant step forward in the area of analog circuit design. As demonstrated in this book, symbolic analysis opens up new possibilities for the development of computer-aided design (CAD) tools that can analyze an analog circuit topology and automatically size the components for a given set of specifications. Symbolic analysis even has the potential to improve the training of young analog circuit designers and to guide more experienced designers through second-order phenomena such as distortion. This book can also serve as an excellent reference for researchers in the analog circuit design area and creators of CAD tools, as it provides a comprehensive overview and comparison of various approaches for analog circuit design automation and an extensive bibliography. The world is essentially analog in nature, hence most electronic systems involve both analog and digital circuitry. As the number of transistors that can be integrated on a single integrated circuit (IC) substrate steadily increases over time, an ever increasing number of systems will be implemented with one, or a few, very complex ICs because of their lower production costs.

The modern electronic testing has a forty year history. Test professionals hold some fairly large conferences and numerous workshops, have a journal, and there are over one hundred books on testing. Still, a full course on testing is offered only at a few universities, mostly by professors who have a research interest in this area. Apparently, most professors would not have taken a course on electronic testing when they were students. Other than the computer engineering curriculum being too crowded, the major reason cited for the absence of a course on electronic testing is the lack of a suitable textbook. For VLSI the foundation was provided by semiconductor device technology, circuit design, and electronic testing. In a computer engineering curriculum, therefore, it is necessary that foundations should be taught before applications. The field of VLSI has expanded to systems-on-a-chip, which include digital, memory, and mixed-signal subsystems. To our knowledge this is the first textbook to cover all three types of electronic circuits. We have written this textbook for an undergraduate "foundations" course on electronic testing. Obviously, it is too voluminous for a one-semester course and a teacher will have to select from the topics. We did not restrict such freedom because the selection may depend upon the individual expertise and interests. Besides, there is merit in having a larger book that will retain its usefulness for the owner even after the completion of the course. With equal tenacity, we address the needs of three other groups of readers.

In two editions spanning more than a decade, The Electrical Engineering Handbook stands as the definitive reference to the multidisciplinary field of electrical engineering. Our knowledge continues to grow, and so does the Handbook. For the third edition, it has expanded into a set of six books carefully focused on a specialized area or field of study. Each book represents a concise yet definitive collection of key concepts, models, and equations in its respective domain, thoughtfully gathered for convenient access. Computers, Software Engineering, and Digital Devices examines digital and logical devices, displays, testing, software, and computers, presenting the fundamental concepts needed to ensure a thorough understanding of each field. It treats the emerging fields of programmable logic, hardware description languages, and parallel computing in detail. Each article includes defining terms, references, and sources of further information. Encompassing the work of the world's foremost experts in their respective specialties, Computers, Software Engineering, and Digital Devices features the latest developments, the broadest scope of coverage, and new material on secure electronic commerce and parallel computing.

The Electrical Engineering Handbook,Second Edition
Integrated Circuit Test Engineering
Analog and Digital
Design of Logic Systems
The Boundary-Scan Handbook
Circuit Design: Know It All

Managing the power consumption of circuits and systems is now considered one of the most important challenges for the semiconductor industry. Elaborate power management strategies, such as dynamic voltage scaling, clock gating or power gating techniques, are used today to control the power dissipation during functional operation. The usage of these strategies has various implications on manufacturing test, and power-aware test is therefore increasingly becoming a major consideration during design-for-test and test preparation for low power devices. This book explores existing solutions for power-aware test and design-for-test of conventional circuits and systems, and surveys test strategies and EDA solutions for testing low power devices.

In 1993, the first edition of The Electrical Engineering Handbook set a new standard for breadth and depth of coverage in an engineering reference work. Now, this classic has been substantially revised and updated to include the latest information on all the important topics in electrical engineering today. Every electrical engineer should have an opportunity to expand his expertise with this definitive guide. In a single volume, this handbook provides a complete reference to answer the questions encountered by practicing engineers in industry, government, or academia. This well-organized book is divided into 12 major sections that encompass the entire field of electrical engineering, including circuits, signal processing, electronics, electromagnetics, electrical effects and devices, and energy, and the emerging trends in the fields of communications, digital devices, computer engineering, systems, and biomedical engineering. A compendium of physical, chemical, material, and mathematical data completes this comprehensive resource. Every major topic is thoroughly covered and every important concept is defined, described, and illustrated. Conceptually challenging but carefully explained articles are equally valuable to the practicing engineer, researchers, and students. A distinguished advisory board and contributors including many of the leading authors, professors, and researchers in the field today assist noted author and professor Richard Dorf in offering complete coverage of this rapidly expanding field. No other single volume available today offers this combination of broad coverage and depth of exploration of the topics. The Electrical Engineering Handbook will be an invaluable resource for electrical engineers for years to come.

This book brings together innovative modelling, simulation and design techniques in CMOS, SOI, GaAs and BJT to achieve successful high-yield manufacture for low-power, high-speed and reliable-by-design analogue and mixed-mode integrated systems.

With the advance of semiconductors and ubiquitous computing, the use of system-on-a-chip (SoC) has become an essential technique to reduce product cost. With this progress and continuous reduction of feature sizes, and the development of very large-scale integration (VLSI) circuits, addressing the harder problems requires fundamental understanding of circuit and layout design issues. Furthermore, engineers can often develop their physical intuition to estimate the behavior of circuits rapidly without relying predominantly on computer-aided design (CAD) tools. Introduction to VLSI Systems: A Logic, Circuit, and System Perspective addresses the need for teaching such a topic in terms of a logic, circuit, and system design perspective. To achieve the above-mentioned goals, this classroom-tested book focuses on: Implementing a digital system as a full-custom integrated circuit Switch logic design and useful paradigms that may apply to various static and dynamic logic families The fabrication and layout designs of complementary metal-oxide-semiconductor (CMOS) VLSI Important issues of modern CMOS processes, including deep submicron devices, circuit optimization, interconnect modeling and optimization, signal integrity, power integrity, clocking and timing, power dissipation, and electrostatic discharge (ESD) Introduction to VLSI Systems builds an understanding of integrated circuits from the bottom up, paying much attention to logic circuit, layout, and system designs. Armed with these tools, readers can not only comprehensively understand the features and limitations of modern VLSI technologies, but also have enough background to adapt to this ever-changing field.

Principles and Practices
System-on-Chip Test Architectures
Integrated Circuit Design and Technology
Essentials of Electronic Testing for Digital, Memory and Mixed-Signal VLSI Circuits
Principles of Testing Electronic Systems
Digital Design and Fabrication

This book is the second edition of Design to Test. The first edition, written by myself and H. Frank Binnendyk and first published in 1982, has undergone several printings and become a standard in many companies, even in some countries. Both Frank and I are very proud of the success that our customers have had in utilizing the information, all of it still applicable to today's electronic designs. But six years is a long time in any technology field. I therefore felt it was time to write a new edition. This new edition, while retaining the basic testability prin ciples first documented six years ago, contains the latest material on state-of-the-art testability techniques for electronic devices, boards, and systems and has been completely rewritten and up dated. Chapter 15 from the first edition has been converted to an appendix. Chapter 6 has been expanded to cover the latest tech nology devices. Chapter 1 has been revised, and several examples throughout the book have been revised and updated. But some times the more things change, the more they stay the same. All of the guidelines and information presented in this book deal with the three basic testability principles-partitioning, control, and visibility. They have not changed in years. But many people have gotten smarter about how to implement those three basic test ability principles, and it is the aim of this text to enlighten the reader regarding those new (and old) testability implementation techniques.

Boundary-Scan, formally known as IEEE/ANSI Standard 1149.1-1990, is a collection of design rules applied principally at the Integrated Circuit (IC) level that allow software to alleviate the growing cost of designing, producing and testing digital systems. A fundamental benefit of the standard is its ability to transform extremely difficult printed circuit board testing problems that could only be attacked with ad-hoc testing methods into well-structured problems that software can easily deal with. IEEE standards, when embraced by practicing engineers, are living entities that grow and change quickly. The Boundary-Scan Handbook, Second Edition: Analog and Digital is intended to describe these standards in simple English rather than the strict and pedantic legalese encountered in the standards. The 1149.1 standard is now over eight years old and has a large infrastructure of support in the electronics industry. Today, the majority of custom ICs and programmable devices contain 1149.1. New applications for the 1149.1 protocol have been introduced, most notably the `In-System Configuration' (ISC) capability for Field Programmable Gate Arrays (FPGAs). The Boundary-Scan Handbook, Second Edition: Analog and Digital updates the information about IEEE Std. 1149.1, including the 1993 supplement that added new silicon functionality and the 1994 supplement that formalized the BSDL language definition. In addition, the new second edition presents completely new information about the newly approved 1149.4 standard often termed `Analog Boundary-Scan'. Along with this is a discussion of Analog Metrology needed to make use of 1149.1. This forms a toolset essential for testing boards and systems of the future.

Includes bibliographical references and index.

Digital Systems Design with FPGAs and CPLDs explains how to design and develop digital electronic systems using programmable logic devices (PLDs). Totally practical in nature, the book features numerous (quantify when known) case study designs using a variety of Field Programmable Gate Array (FPGA) and Complex Programmable Logic Devices (CPLD), for a range of applications from control and instrumentation to semiconductor automatic test equipment. Key features include: * Case studies that provide a walk through of the design process, highlighting the trade-offs involved. * Discussion of real world issues such as choice of device, pin-out, power supply, power supply decoupling, signal integrity- for embedding FPGAs within a PCB based design. With this book engineers will be able to: * Use PLD technology to develop digital and mixed signal electronic systems * Develop PLD based designs using both schematic capture and VHDL synthesis techniques * Interface a PLD to digital and mixed-signal systems * Undertake complete design exercises from design concept through to the build and test of PLD based electronic hardware This book will be ideal for electronic and computer engineering students taking a practical or Lab based course on digital systems development using PLDs and for engineers in industry looking for concrete advice on developing a digital system using a FPGA or CPLD as its core. Case studies that provide a walk through of the design process, highlighting the trade-offs involved. Discussion of real world issues such as choice of device, pin-out, power supply, power supply decoupling, signal integrity- for embedding FPGAs within a PCB based design.

The Electronic Design Automation Handbook
Patents
Using HDL Models and Architectures
A Guide to DFT and Other Techniques
Digital Design
Nanometer Design for Testability

This popular volume provides a solid foundation in the elements of basic digital electronics and switching theory that are used in most practical digital design today -- and builds on that theory with discussions of real-world digital components, design methodologies, and tools. Covers a full range of topics -- number systems and codes, digital circuits, combinational logic design principles and practices, combinational logic design with PLDs, sequential logic design principles and practices, sequential logic design with PLDs, memory, and additional real-world topics (e.g., computer-aided engineering tools, design for testability, estimating digital system reliability, and transmission lines, reflections, and termination). This edition introduces PLDs as soon as possible, emphasizes CMOS logic families and introduces digital circuits in a strongly technology-independent fashion, covers the latest Generic Array Logic (GAL) devices, offers expanded coverage of ROM and RAM system-level design, and provides additional design examples. For those needing a solid introduction or review of the principles and practices of modern digital design. Previously announced in Oct. 1992 PTR Catalogue.

Modern electronics testing has a legacy of more than 40 years. The introduction of new technologies, especially nanometer technologies with 90nm or smaller geometry, has allowed the semiconductor industry to keep pace with the increased performance-capacity demands from consumers. As a result, semiconductor test costs have been growing steadily and typically amount to 40% of today's overall product cost. This book is a comprehensive guide to new VLSI Testing and Design-for-Testability techniques that will allow students, researchers, DFT practitioners, and VLSI designers to master quickly System-on-Chip Test architectures, for test debug and diagnosis of digital, memory, and analog/mixed-signal designs. Emphasizes VLSI Test principles and Design for Testability architectures, with numerous illustrations/examples. Most up-to-date coverage available, including Fault Tolerance, Low-Power Testing, Defect and Error Tolerance, Network-on-Chip (NOC) Testing, Software-Based Self-Testing, FPGA Testing, MEMS Testing, and System-In-Package (SIP) Testing, which are not yet available in any testing book. Covers the entire spectrum of VLSI testing and DFT architectures, from digital and analog, to memory circuits, and fault diagnosis and self-repair from digital to memory circuits. Discusses future nanotechnology test trends and challenges facing the nanometer design era; promising nanotechnology test techniques, including Quantum-Dots, Cellular Automata, Carbon-Nanotubes, and Hybrid Semiconductor/Nanowire/Molecular Computing. Practical problems at the end of each chapter for students.

DIGITAL SYSTEMS DESIGN USING VERILOG integrates coverage of logic design principles, Verilog as a hardware design language, and FPGA implementation to help electrical and computer engineering students master the process of designing and testing new hardware configurations. A Verilog equivalent of authors Roth and John's previous successful text using VHDL, this practical book presents Verilog constructs side-by-side with hardware, encouraging students to think in terms of desired hardware while writing synthesizable Verilog. Following a review of the basic concepts of logic design, the authors introduce the basics of Verilog using simple combinational circuit examples, followed by models for simple sequential circuits. Subsequent chapters ask readers to tackle more and more complex designs. Important Notice: Media content referenced within the product description or the product text may not be available in the ebook version.

Top-down approach to practical, tool-independent, digital circuit design, reflecting how circuits are designed.

Microelectronics Fialure Analysis Desk Reference, Seventh Edition
Low-Power High-Resolution Analog to Digital Converters
Design for Maintainability
Digital System Test and Testable Design
Symbolic Analysis for Automated Design of Analog Integrated Circuits
Computers, Software Engineering, and Digital Devices

Digital Circuit TestingA Guide to DFT and Other TechniquesElsevier

Your road map for meeting today's digital testing challenges Today, digital logic devices are common in products that impact public safety, including applications in transportation and human implants. Accurate testing has become more critical to reliability, safety, and the bottom line. Yet, as digital systems become more ubiquitous and complex, the challenge of testing them has become more difficult. As one development group designing a RISC stated, "the work required to . . . test a chip of this size approached the amount of effort required to design it." A valued reference for nearly two decades, Digital Logic Testing and Simulation has been significantly revised and updated for designers and test engineers who must meet this challenge. There is no single solution to the testing problem. Organized in an easy-to-follow, sequential format, this Second Edition familiarizes the reader with the many different strategies for testing and their applications, and assesses the strengths and weaknesses of the various approaches. The book reviews the building blocks of a successful testing strategy and guides the reader on choosing the best solution for a particular application. Digital Logic Testing and Simulation, Second Edition covers such key topics as: * Binary Decision Diagrams (BDDs) and cycle-based simulation * Tester architectures/Standard Test Interface Language (STIL) * Practical algorithms written in a Hardware Design Language (HDL) * Fault tolerance * Behavioral Automatic Test Pattern Generation (ATPG) * The development of the Test Design Expert (TDX), the many obstacles encountered and lessons learned in creating this novel testing approach Up-to-date and comprehensive, Digital Logic Testing and Simulation is an important resource for anyone charged with pinpointing faulty products and assuring quality, safety, and profitability.

With the fast advancement of CMOS fabrication technology, more and more signal-processing functions are implemented in the digital domain for a lower cost, lower power consumption, higher yield, and higher re-configurability. This has recently generated a great demand for low-power, low-voltage A/D converters that can be realized in a mainstream deep-submicron CMOS technology. However, the discrepancies between lithography wavelengths and circuit feature sizes are increasing. Lower power supply voltages significantly reduce noise margins and increase variations in process, device and design parameters. Consequently, it is steadily more difficult to control the fabrication process precisely enough to maintain uniformity. The inherent randomness of materials used in fabrication at nanoscopic scales means that performance will be increasingly variable, not only from die-to-die but also within each individual die. Parametric variability will be compounded by degradation in nanoscale integrated circuits resulting in instability of parameters over time, eventually leading to the development of faults. Process variation cannot be solved by improving manufacturing tolerances; variability must be reduced by new device technology or managed by design in order for scaling to continue. Similarly, within-die performance variation also imposes new challenges for test methods. In an attempt to address these issues, Low-Power High-Resolution Analog-to-Digital Converters specifically focus on: i) improving the power efficiency for the high-speed, and low spurious spectral A/D conversion performance by exploring the potential of low-voltage analog design and calibration techniques, respectively, and ii) development of circuit techniques and algorithms to enhance testing and debugging potential to detect errors dynamically, to isolate and confine faults, and to recover errors continuously. The feasibility of the described methods has been verified by measurements from the silicon prototypes fabricated in standard 180nm, 90nm and 65nm CMOS technology.

Using the book and the software provided with it, the reader can build his/her own tester arrangement to investigate key aspects of analog-, digital- and mixed system circuits Plan of attack based on traditional testing, circuit design and circuit manufacture allows the reader to appreciate a testing regime from the point of view of all the participating interests Worked examples based on theoretical bookwork, practical experimentation and simulation exercises teach the reader how to test circuits thoroughly and effectively

Test and Design-for-Testability in Mixed-Signal Integrated Circuits
Introduction to VLSI Systems
Design, Test and Calibration
A Logic, Circuit, and System Perspective
Delay Fault Testing for VLSI Circuits
VLSI Design and Test for Systems Dependability

This is a new type of edited volume in the Frontiers in Electronic Testing book series devoted to recent advances in electronic circuits testing. The book is a comprehensive elaboration on important topics which capture major research and development efforts today. "Hot" topics of current interest to test technology community have been selected, and the authors are key contributors in the corresponding topics.

This book discusses the new roles that the VLSI (very-large-scale integration of semiconductor circuits) is taking for the safe, secure, and dependable design and operation of electronic systems. The book consists of three parts. Part I, as a general introduction to this vital topic, describes how electronic systems are designed and tested with particular emphasis on dependability engineering, where the simultaneous assessment of the detrimental outcome of failures and cost of their containment is made. This section also describes the related research project "Dependable VLSI Systems," in which the editor and authors of the book were involved for 8 years. Part II addresses various threats to the dependability of VLSIs as key systems components, including time-dependent degradations, variations in device characteristics, ionizing radiation, electromagnetic interference, design errors, and tampering, with discussion of technologies to counter those threats. Part III elaborates on the design and test technologies for dependability in such applications as control of robots and vehicles, data processing, and storage in a cloud environment and heterogeneous wireless telecommunications. This book is intended to be used as a reference for engineers who work on the design and testing of VLSI systems with particular attention to dependability. It can be used as a textbook in graduate courses as well. Readers interested in dependable systems from social and industrial-economic perspectives will also benefit from the discussions in this book.

When I attended college we studied vacuum tubes in our junior year. At that time an average radio had ?ve vacuum tubes and better ones even seven. Then transistors appeared in 1960s. A good radio was judged to be one with more thententransistors. Latergoodradioshad15-20transistors and after that everyone stopped counting transistors. Today modern processors runing personal computers have over 10milliontransistorsandmoremillionswillbeaddedevery year. The difference between 20 and 20M is in complexity, methodology and business models. Designs with 20 tr- sistors are easily generated by design engineers without any tools, whilst designs with 20M transistors can not be done by humans in reasonable time without the help of Prof. Dr. Gajski demonstrates the Y-chart automation. This difference in complexity introduced a paradigm shift which required sophisticated methods and tools, and introduced design automation into design practice. By the decomposition of the design process into many tasks and abstraction levels the methodology of designing chips or systems has also evolved. Similarly, the business model has changed from vertical integration, in which one company did all the tasks from product speci?cation to manufacturing, to globally distributed, client server production in which most of the design and manufacturing tasks are outsourced.

"This book covers aspects of system design and efficient modelling, and also introduces various fault models and fault mechanisms associated with digital circuits integrated into System on Chip (SoC), Multi-Processor System-on Chip (MPSoC) or Network on Chip (NoC)"--

Design to Test
Advances in Electronic Testing
Digital Systems Design Using Verilog
Power-Aware Testing and Test Strategies for Low Power Devices
IDDQ Testing of VLSI Circuits
From VLSI Architectures to CMOS Fabrication

Test and Design-for-Testability in Mixed-Signal Integrated Circuits deals with test and design for test of analog and mixed-signal integrated circuits. Especially in System-on-Chip (SoC), where different technologies are intertwined (analog, digital, sensors, RF); test is becoming a true bottleneck of present and future IC projects. Linking design and test in these heterogeneous systems will have a tremendous impact in terms of test time, cost and proficiency. Although it is recognized as a key issue for developing complex ICs, there is still a lack of structured reference presenting the major topics in this area. The aim of this book is to present basic concepts and new ideas in a manner understandable for both professionals and students. Since this is an active research field, a comprehensive state-of-the-art overview is very valuable, introducing the main problems as well as the ways of solution that seem promising, emphasizing their basis, strengths and weaknesses. In essence, several topics are presented in detail. First of all, techniques for the efficient use of DSP-based test and CAD test tools. Standardization is another topic considered in the book, with focus on the IEEE 1149.4. Also addressed in depth is the connecting design and test by means of using high-level (behavioural) description techniques, specific examples are given. Another issue is related to test techniques for well-defined classes of integrated blocks, like data converters and phase-locked-loops. Besides these specification-driven testing techniques, fault-driven approaches are described as they offer potential solutions which are more similar to digital test methods. Finally, in Design-for-Testability and Built-In-Self-Test, two other concepts that were taken from digital design, are introduced in an analog context and illustrated for the case of integrated filters. In summary, the purpose of this book is to provide a glimpse on recent research results in the area of testing mixed-signal integrated circuits, specifically in the topics mentioned above. Much of the work reported herein has been performed within cooperative European Research Projects, in which the authors of the different chapters have actively collaborated. It is a representative snapshot of the current state-of-the-art in this emergent field.

The Newnes Know It All Series takes the best of what our authors have written to create hard-working desk references that will be an engineer's first port of call for key information, design techniques and rules of thumb. Guaranteed not to gather dust on a shelf! Electronics Engineers need to master a wide area of topics to excel. The Circuit Design Know It All covers every angle including semiconductors, IC Design and Fabrication, Computer-Aided Design, as well as Programmable Logic Design. • A 360-degree view from our best-selling authors • Topics include fundamentals, Analog, Linear, and Digital circuits • The ultimate hard-working desk reference; all the essential information, techniques and tricks of the trade in one volume

In the early days of digital design, we were concerned with the logical correctness of circuits. We knew that if we slowed down the clock signal sufficiently, the circuit would function correctly. With improvements in the semiconductor process technology, our expectations on speed have soared. A frequently asked question in the last decade has been how fast can the clock run. This puts significant demands on timing analysis and delay testing. Fueled by the above events, a tremendous growth has occurred in the research on

delay testing. Recent work includes fault models, algorithms for test generation and fault simulation, and methods for design and synthesis for testability. The authors of this book, Angela Krstic and Tim Cheng, have personally contributed to this research. Now they do an even greater service to the profession by collecting the work of a large number of researchers. In addition to expounding such a great deal of information, they have delivered it with utmost clarity. To further the reader's understanding many key concepts are illustrated by simple examples. The basic ideas of delay testing have reached a level of maturity that makes them suitable for practice. In that sense, this book is the best x DELAY FAULT TESTING FOR VLSI CIRCUITS available guide for an engineer designing or testing VLSI systems. Tech niques for path delay testing and for use of slower test equipment to test high-speed circuits are of particular interest.

Recent technological advances have created a testing crisis in the electronics industry--smaller, more highly integrated electronic circuits and new packaging techniques make it increasingly difficult to physically access test nodes. New testing methods are needed for the next generation of electronic equipment and a great deal of emphasis is being placed on the development of these methods. Some of the techniques now becoming popular include design for testability (DFT), built-in self-test (BIST), and automatic test vector generation (ATVG). This book will provide a practical introduction to these and other testing techniques. For each technique introduced, the author provides real-world examples so the reader can achieve a working knowledge of how to choose and apply these increasingly important testing methods.

Design and Test Technology for Dependable Systems-on-chip

Official Gazette of the United States Patent and Trademark Office

Challenges and Methodologies

Microelectronics Failure Analysis

A Definitive Guide for Electronic Design, Manufacture, and Service

Digital Systems Design with FPGAs and CPLDs

Power supply current monitoring to detect CMOS IC defects during production testing quietly laid down its roots in the mid-1970s. Both Sandia Labs and RCA in the United States and Philips Labs in the Netherlands practiced this procedure on their CMOS ICs. At that time, this practice stemmed simply from an intuitive sense that CMOS ICs showing abnormal quiescent power supply current (IDDQ) contained defects. Later, this intuition was supported by data and analysis in the 1980s by Levi (RACD, Malaiya and Su (SUNY-Binghamton), Soden and Hawkins (Sandia Labs and the University of New Mexico), Jacomino and co-workers (Laboratoire d'Automatique de Grenoble), and Maly and co-workers (Carnegie Mellon University). Interest in IDDQ testing has advanced beyond the data reported in the 1980s and is now focused on applications and evaluations involving larger volumes of ICs that improve quality beyond what can be achieved by previous conventional means. In the conventional style of testing one attempts to propagate the logic states of the suspended nodes to primary outputs. This is done for all or most nodes of the circuit. For sequential circuits, in particular, the complexity of finding suitable tests is very high. In comparison, the IDDQ test does not observe the logic states, but measures the integrated current that leaks through all gates. In other words, it is like measuring a patient's temperature to determine the state of health. Despite perceived advantages, during the years that followed its initial announcements, skepticism about the practicality of IDDQ testing prevailed. The idea, however, provided a great opportunity to researchers. New results on test generation, fault simulation, design for testability, built-in self-test, and diagnosis for this style of testing have since been reported. After a decade of research, we are definitely closer to practice.

Digital Circuit Testing